

Appendix B

NFC

Device Under Test Properties

Model	Dimensions [mm]
N5510L	145.5 x 72.5 x 12.5

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 0--	13.600, 13600	18.19	0.783	53.9

Hardware Setup

Phantom	TSL	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – 2227	HSL13MHz	EX3DV4 – SN7858, 2025-02-20	DAE4ip Sn1847, 2024-12-31

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-11-21, 16:48	2025-11-21, 16:51
psSAR1g [W/Kg]	0.043	0.041
psSAR10g [W/Kg]	0.029	0.014
Power Drift [dB]	0.06	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		42.6
Dist 3dB Peak [mm]		14.8

